

8CH HIGH-VOLTAGE SOURCE DRIVER

The KID65783AP/AF is comprised of eight source current transistor array. This driver is specifically designed for fluorescent display applications. Applications include relay, hammer and lamp drivers.

FEATURES

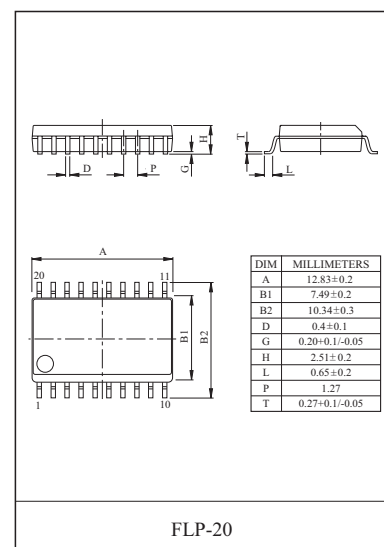
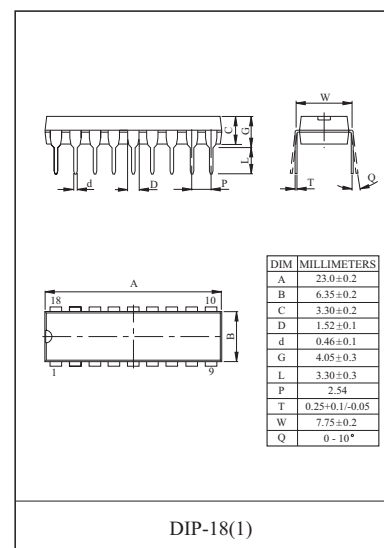
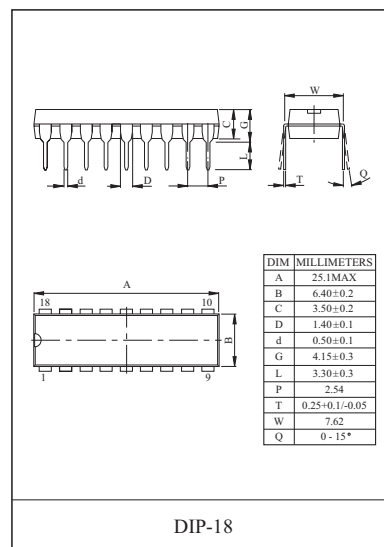
- High Output Voltage : $V_{CC}=50V(\text{Min.})$.
- Output Current (Single Output) $I_{OUT} : -500mA(\text{Min.})$.
- Output Clamp Diodes.
- Single Supply Voltage.
- Input Compatible With Various Types of Logic.
- Package Type-AP : DIP-18pin. DIP-18(1)Pin
- Package Type AF : FLP-20pin.

TYPE	DESIGNATION
KID65783AP/AF	TTL, 5V CMOS

MAXIMUM RATINGS ($T_a=25^\circ\text{C}$)

CHARACTERISTIC	SYMBOL	RATING	UNIT
Supply Voltage	V_{CC}	50	V
Output Current	I_{OUT}	-500	mA/ch
Input Voltage	V_{IN}	15	V
Clamp Diode Reverse Voltage	V_R	50	V
Clamp Diode Forward Current	I_F	500	mA
Power Dissipation	AP	$P_D(\text{Note})$	W
	AF		
Operating Temperature	T_{opr}	-40 85	
Storage Temperature	T_{stg}	-55 150	

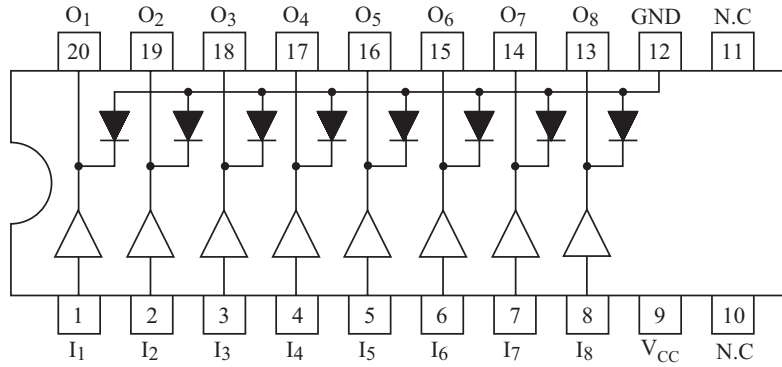
Note) Delated above 25°C in the proportion of 11.7W/ (AP Type), 7.7W/ (AF Type).



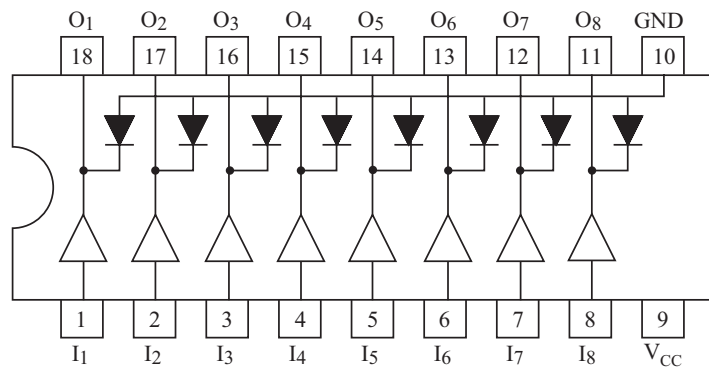
KID65783AP/AF

PIN CONNECION (TOP VIEW)

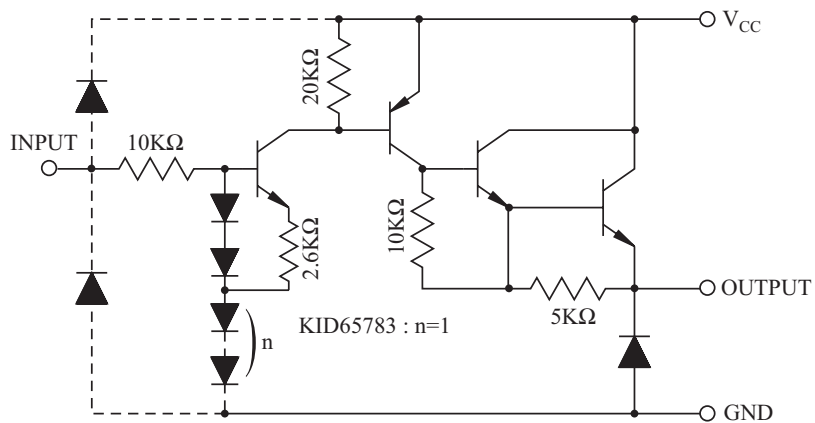
AF-TYPE (FLP-20 package)



AP-TYPE (DIP-18 package)



SCHEMATICS (EACH DRIVER)



(Note) The input and output parasitic diodes cannot be used as clamp diodes.

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RECOMMENDED OPERATING CONDITIONS (Ta=-40 ~ 85 °C)

CHARACTERISTIC		SYMBOL	TEST CONDITION		MIN.	TYP.	MAX.	UNIT
Supply Voltage		V _{CC}	-		-	-	50	V
Output Current	AP	I _{OUT}	Ta=85 Tj=120 Tpw=25mS	Duty=10% 8 Circuits	-	-	-260	mA/ch
				Duty=50% 8 Circuits	-	-	-59	
	AF			Duty=10% 8 Circuits	-	-	-180	
				Duty=50% 8 Circuits	-	-	-38	
Input Voltage		V _{IN}	-		-	-	12	V
Input Voltage	Output ON	V _{IN (ON)}	-		2.0	5.0	15	V
	Output OFF	V _{IN (OFF)}	-		0	-	0.8	
Clamp Diode Reverse Voltage	AP	V _R	-		-	-	50	V
	AF				-	-	35	
Clamp Diode Forward Current		I _F	-		-	-	400	mA
Power Dissipation	AP	P _D	-		-	-	0.52	W
	AF				-	-	0.35	

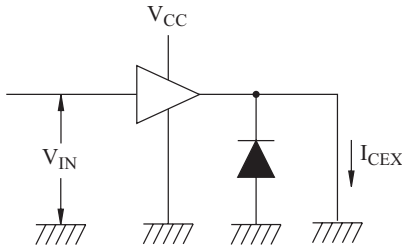
ELECTRICAL CHARACTERISTICS (Ta=25 °C)

CHARACTERISTIC	SYMBOL	TEST CIRCUIT	TEST CONDITION	MIN.	TYP.	MAX.	UNIT
Output Leakage Current	I_{CEX}	1	$V_{CC}=V_{CC\ MAX}$, $V_{IN}=0.4V$ Ta=25	-	-	100	μA
Output Saturation Voltage	$V_{CE(sat)}$	2	$V_{IN}=V_{IN(ON)}$, $I_{OUT}=-350mA$	-	-	2.0	V
			$V_{IN}=V_{IN(ON)}$, $I_{OUT}=-225mA$	-	-	1.9	
			$V_{IN}=V_{IN(ON)}$, $I_{OUT}=-100mA$	-	-	1.8	
Input Current	$I_{IN(ON)}$	3	$V_{IN}=2.4V$	-	36	52	μA
			$V_{IN}=3.85V$	-	180	260	
Input Voltage	$V_{IN(ON)}$	4	$V_{CE}=2.0V$, $I_{OUT}=-350mA$	-	-	2.0	V
	$V_{IN(OFF)}$		$I_{OUT}=-500\ \mu A$	0.8	-	-	
Supply Current	$I_{CC(ON)}$	3	$V_{IN}=V_{IN(ON)}$, $V_{CC}=50V$	-	-	2.5	mA/ch
Clamp Diode Reverse Current	I_R	5	$V_R=50V$	-	-	50	μA
Clamp Diode Forward Voltage	V_F	6	$I_F=350mA$	-	-	2.0	V
Turn-On Delay	t_{ON}	7	$V_{CC}=V_{CC\ MAX}$, $R_L=125\ \Omega$ $C_L=15pF$	-	0.15	-	μs
Turn-Off Delay	t_{OFF}			-	1.8	-	

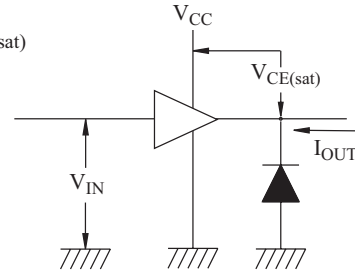
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TEST CIRCUIT

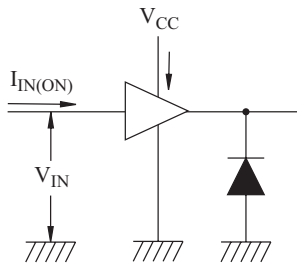
1. I_{CEX}



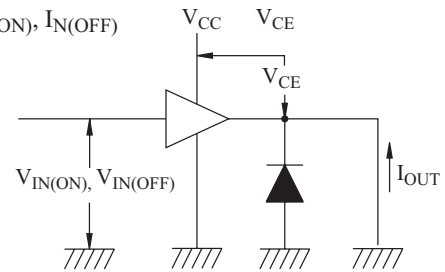
2. $V_{CE(sat)}$



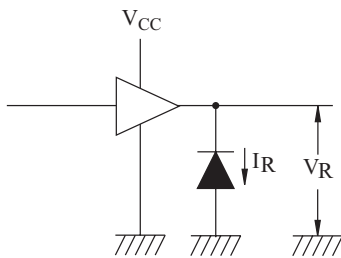
3. $I_{IN(ON)}$, I_{CC}



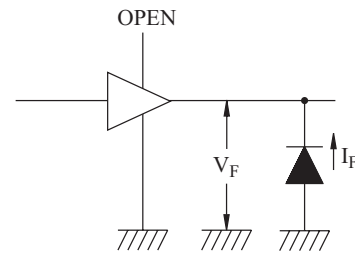
4. $V_{IN(ON)}$, $I_{N(OFF)}$



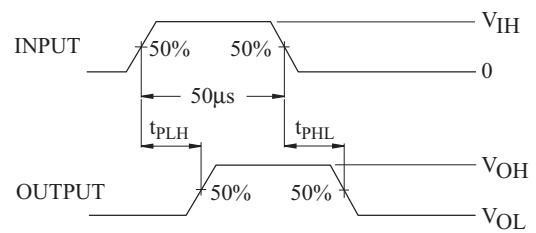
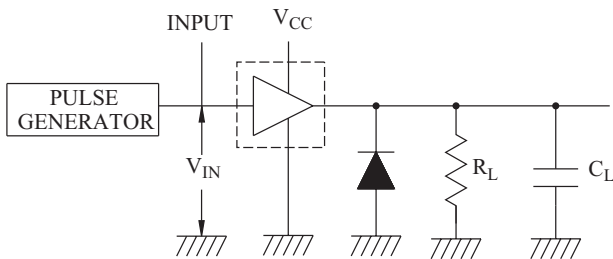
5. I_R



6. V_F



7. t_{ON} , t_{OFF}

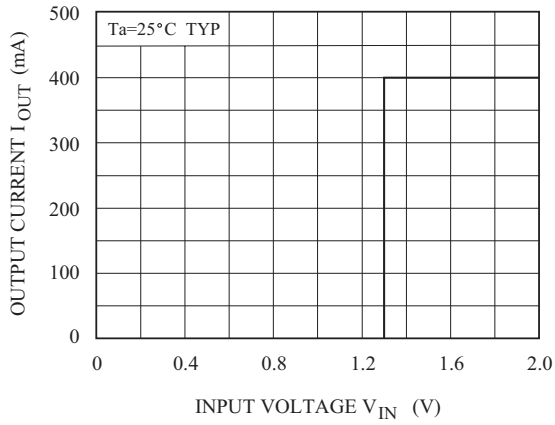


(Note 1) Pulse width 50 μ S, duty cycle 10%
Output impedance 50 Ω , $t \leq 5$ ns, $t \leq 10$ ns

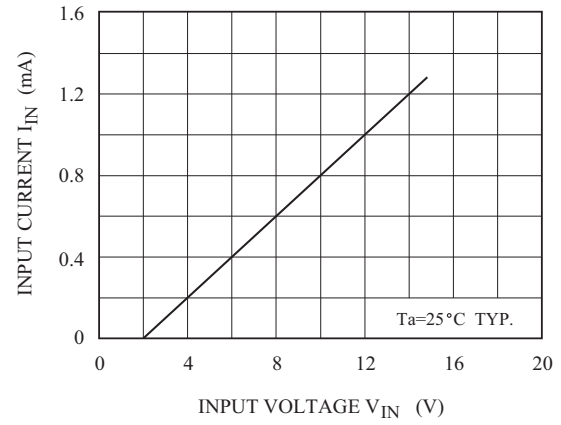
(Note 2) C_L includes probe and jig capacitance

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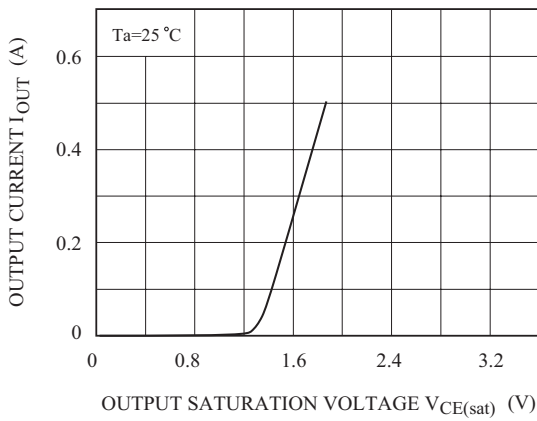
$I_{OUT} - V_{IN}$



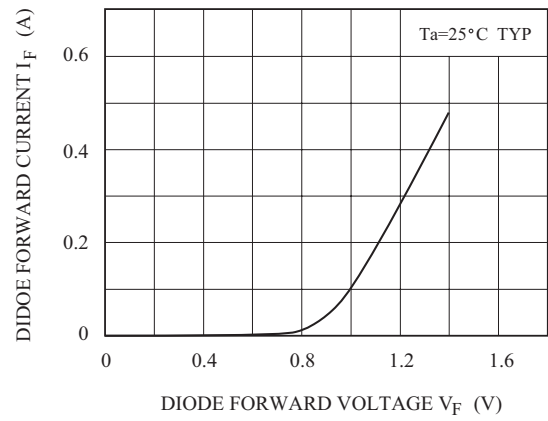
$I_{IN} - V_{IN}$



$I_{OUT} - V_{CE(sat)}$



$I_F - V_F$



$P_D - T_a$

